

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	55	((CHUNG-SAM) near2 (JUN)).INV.	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/16 13:14
L3	59	((SANG-MUN) near2 (CHON)).INV.	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/16 13:19
L4	24	((SUN-YONG) near2 (CHOI)).INV.	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/16 13:21
L5	35	((DONG-JIN) near2 (PARK)).INV.	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/16 13:22
L6	8	((JEONG-HYUN) near2 (CHOI)).INV.	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/16 13:24
S1	37073	fft or fast adj fourier adj transform	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/15 12:57
S2	37073	fft or (fast adj fourier adj transform)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/15 12:57
S3	69458	(scanning adj electron adj microscope) or (electron adj microscope)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/15 12:58
S4	332	S2 and S3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/15 12:58
S5	3245791	(sample) or (wafer) or (IC) or (integrated adj circuit) or (IC adj chip)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/15 13:00

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S6	303	S4 and S5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/15 13:00
S7	69630	(inspect\$3 or analyzing or determining or finding) same (defects or abnormalities)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/15 13:01
S8	74077	(inspect\$3 or analyzing or determining or finding or discrimi\$5) same (defects or abnormalities)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/15 13:02
S9	69	S6 and S8	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/15 13:02
S10	63	etching same trace same (line adj width)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/02/15 13:04
S12	7	("4242635" "4466746" "4668916" "4682857" "6121059" "6559670" "6657447").PN. OR ("6842021").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/02/15 13:19